CLAIMS

What is claimed is:

1	1.	A method for testing cache performance of a processor design, the method		
2	compr	comprising:		
3		searching a file that contains cache test results for a lot of wafers; and		
4		determining at least one cache array location in at least one processor in the lot		
5	wafers	processor for which a cache test has failed.		
1	2.	The method of claim 1, wherein the searching the file comprises parsing the		
2	file.			
1	3.	The method of claim 1, wherein the searching the file comprises opening the		
2	file and	d parsing the file.		
1	4.	The method of claim 1, wherein the determining the at least one cache array		
2	locatio	n comprises determining a column and row location in the corresponding cache		
3	array.			
1	5.	The method of claim 1, further comprising developing a cache array repair		
2	signatu	re based on the at least one cache array location for which a cache test has		
3	failed.			
l	6.	The method of claim 5, wherein the cache array repair signature defines a		
2	cache a	rray location associated with the processor design which has failed the cache		
3	test in a	statistically relevant percentage of the processors in the lot.		

1	7.	A system for testing cache performance of a processor design, the system	
2	comprising:		
3		a parser module for searching a file that contains cache test results for a lot of	
4	wafers;		
5		a composite repair failure identification module for determining cache array	
6	locations for which a cache test has failed; and		
7		a cache array repair signature module for determining at least one cache array	
8	location associated with the processor design which has failed the cache test in a		
9	statistically relevant percentage of the processors in the lot.		
1	8.	The system of claim 7, wherein the parser module is configured to open the	
2	file that contains the cache test results.		
1	9.	The system of claim 7, wherein the parser module, the composite repair failure	
2	identifi	cation module, and the cache array repair signature module comprise software	
3	that is	executed by a processor.	
1	10.	The system of claim 7, wherein the cache array repair signature module is	
2	configu	ared to determine a column and row location in the corresponding cache array.	

1 11. A cache yield analysis program embodied in a computer-readable medium, the 2 program comprising: logic configured to search a file that contains test results for a lot of wafers and 3 determine cache array locations for processors in the lot for which a cache test has 4 5 failed; and 6 logic configured to determine a cache array repair signature that defines at 7 least one cache array location associated with the processor design which has failed 8 the cache test in a statistically relevant percentage of the processors in the lot. 1 12. The program of claim 11, wherein the logic configured to determine a cache 2 array repair signature is further configured to determine a column and row location in 3 the corresponding cache array.

1	13.	A system for testing cache performance of a processor design, the system
2	comp	rising:
3		means for searching a file that contains test results for a lot of wafers;
4		means for determining cache array locations for processors in the lot for which
5	a cach	ne test has failed; and
5.		means for generating a cache array repair signature that defines at least one
7	cache	array location associated with the processor design which has failed the cache
3	test in	a statistically relevant percentage of the processors in the lot.